



IN THE UNITED STATES PATENT AND TRADEMARK OFFICE
(Case No. 219.003-US)

the Application of: Yamada

Serial No: 09/865,528

Filed: May 29, 2001

Title: Semiconductor Device Test Method and
Semiconductor Device Tester

Commissioner for Patents
P.O. Box 1450
Alexandria, VA 22313-1450

) Group
) Art Unit: 2829
)
) Before
) Examiner: V. Nguyen

I hereby certify that this correspondence
is being deposited with the United States
Postal Service as first class mail with
sufficient postage in an envelope
addressed to the Commissioner for
Patents, P.O. Box 1450, Alexandria, VA
22313-1450 on March 15, 2004

Michiko Sato
(person signing this certificate)

Michiko Sato
Signature

INFORMATION DISCLOSURE STATEMENT

Dear Sir:

Submitted herewith are two (2) sheets of a modified Form PTO-1449. A copy of each document cited on the attached Form PTO-1449 is also submitted.

Notably, the documents listed on the attached Form PTO-1449 were identified and/or cited in applications (namely, U.S. App. Serial Nos. 09/451,440 and 09/702,831) that include subject matter which is similar to that in the above-reference application.

It is respectfully requested that the Examiner make his/her consideration of these documents formally of record with the initial Office Action.

Respectfully submitted,

Neil A. Steinberg, Reg. No. 34,735
650-968-8079

Date: March 15, 2004



PTO-1449 (Modified) U. S. DEPARTMENT OF COMMERCE PATENT AND TRADEMARK OFFICE INFORMATION DISCLOSURE STATEMENT BY APPLICANT	ATTY. DOCKET NO. 219.003-US	SERIAL NUMBER 09/865,528
	APPLICANT(S) Yamada	
	FILING DATE May 29, 2001	GROUP ART UNIT 2829

U. S. PATENT DOCUMENTS

EXAMINER INITIALS	DOCUMENT NUMBER	DATE	NAME	CLASS	SUB CLASS	FILING DATE
	4,988,877	1/1991	Stokowski et al.			
	4,949,162	8/1990	Tamaki et al.			
	5,001,536	3/1991	Fukuzawa et al.			
	5,327,012	7/1994	Yano et al.			
	5,412,210	5/1995	Todokoro et al.			
	5,637,186	6/1997	Liu et al.			
	5,780,870	7/1998	Maeda et al.			

FOREIGN PATENT DOCUMENTS

EXAMINER INITIALS	DOCUMENT NUMBER	DATE	COUNTRY	CLASS	SUB CLASS	TRANSLATION YES/NO
	6-273297	9/1994	Japan			
	7-66172	3/1995	Japan			
	57-6310	1/1996	Japan			
	8-313244	11/1996	Japan			
	9-61142	3/1997	Japan			
	10-300450	11/1998	Japan			
	50-63990	5/1975	Japan			
	62-19707	1/1987	Japan			
	8-5528	1/1996	Japan			

OTHER DOCUMENTS (Including Author, Title, Date, Pertinent Pages, Etc.)

EXAMINER	DATE CONSIDERED
----------	-----------------

EXAMINER: Initial citation if reference was considered. Draw line through citation if not in conformance to MPEP 609 and not considered. Include copy of this form with next communication to applicant.

PTO-1449 (Modified) U.S. DEPARTMENT OF COMMERCE PATENT AND TRADEMARK OFFICE INFORMATION DISCLOSURE STATEMENT BY APPLICANT		ATTY. DOCKET NO. 219.003-US	SERIAL NUMBER 09/865,528
APPLICANT(S) Yamada			
FILING DATE May 29, 2001		GROUP ART UNIT 2829	

U.S. PATENT DOCUMENTS						
EXAMINER INITIALS	DOCUMENT NUMBER	DATE	NAME	CLASS	SUB CLASS	FILING DATE
	5,900,645	5/1999	Yamada			
	6,037,588	3/2000	Liu et al.			
	6,127,193	10/2000	Bang et al.			
	6,317,514	11/2001	Reinhorn et al.			
	5,280,176	1/1994	Jach et al.			

FOREIGN PATENT DOCUMENTS

EXAMINER INITIALS	DOCUMENT NUMBER	DATE	COUNTRY	CLASS	SUB CLASS	TRANSLATION YES/NO
	3-205573	9/1991	Japan			
	4-62857	2/1992	Japan			
	10-281746	10/1998	Japan			
	11-26343	1/1999	Japan			
	2000-164715	6/2000	Japan			
	2000-180143	6/2000	Japan			
	2000-124276	4/2000	Japan			
	2000-174077	6/2000	Japan			
	62-19707	1/1987	Japan			

OTHER DOCUMENTS (Including Author, Title, Date, Pertinent Pages, Etc.)

EXAMINER	DATE CONSIDERED
----------	-----------------

EXAMINER: Initial citation if reference was considered. Draw line through citation if not in conformance to MPEP 609 and not considered. Include copy of this form with next communication to applicant.